



P-Channel 1.2-V (G-S) MOSFET

PRODUCT SUMMARY			
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^c	Q _g (Typ)
- 8	0.078 at V _{GS} = - 4.5 V	- 1.6	10.5 nC
	0.095 at V _{GS} = - 2.5 V	- 1.6	
	0.115 at V _{GS} = - 1.8 V	- 1.6	
	0.153 at V _{GS} = - 1.5 V	- 1.6	
	0.424 at V _{GS} = - 1.2 V	- 1.6 ^b	

FEATURES

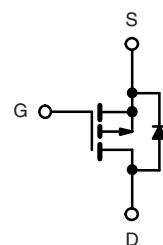
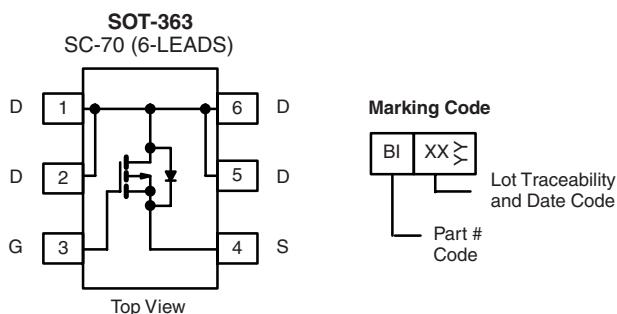
- TrenchFET® Power MOSFET
- Ultra-Low On-Resistance



RoHS
COMPLIANT

APPLICATIONS

- Load Switch for Portable Devices
 - Guaranteed Operation at V_{GS} = 1.2 V
 - Critical for Optimized Design and Longer Battery Life



Ordering Information: Si1499DH-T1-E3 (Lead (Pb)-free)

ABSOLUTE MAXIMUM RATINGS T_A = 25 °C, unless otherwise noted

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	- 8	V
Gate-Source Voltage	V _{GS}	± 5	
Continuous Drain Current (T _J = 150 °C) ^{a, b}	T _C = 25 °C	- 1.6 ^c	A
	T _C = 70 °C	- 1.6 ^c	
	T _A = 25 °C	- 1.6 ^{a, b, c}	
	T _A = 70 °C	- 1.6 ^{a, b, c}	
Pulsed Drain Current (10 µs Pulse Width)	I _{DM}	- 6.5 ^c	
Continuous Source-Drain Diode Current ^{a, b}	T _C = 25 °C	- 1.6 ^c	
	T _A = 25 °C	- 1.3 ^{a, b}	
Maximum Power Dissipation ^{a, b}	T _C = 25 °C	2.78	W
	T _C = 70 °C	1.78	
	T _A = 25 °C	2.5 ^{a, b}	
	T _A = 70 °C	1 ^{a, b}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C
Soldering Recommendations (Peak Temperature) ^{c, d}		260	

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{a, d}	t ≤ 5 s	R _{thJA}	60	°C/W
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	34	

Notes:

- a. Surface Mounted on 1" x 1" FR4 board.
- b. t = 5 s.
- c. Package limited.
- d. Maximum under Steady State conditions is 125 °C/W.

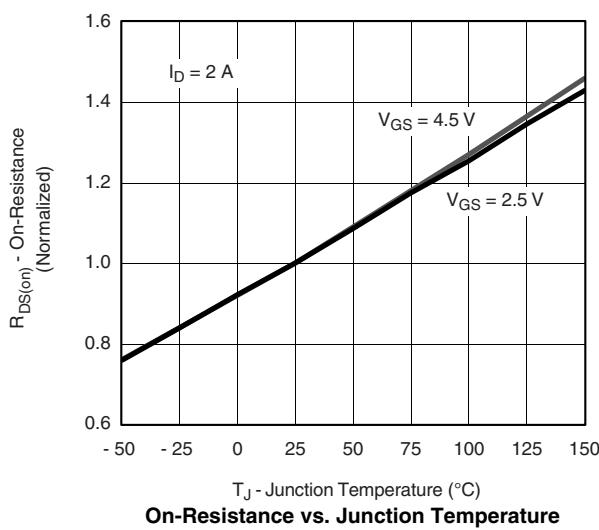
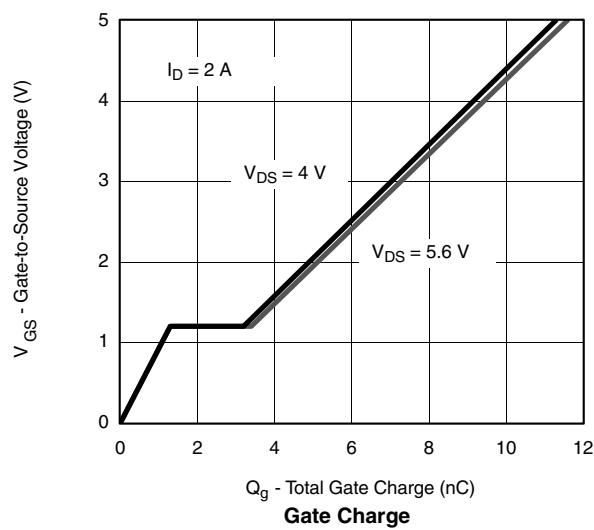
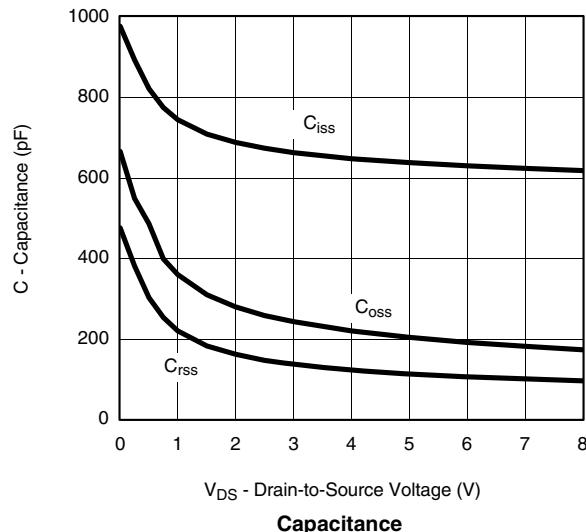
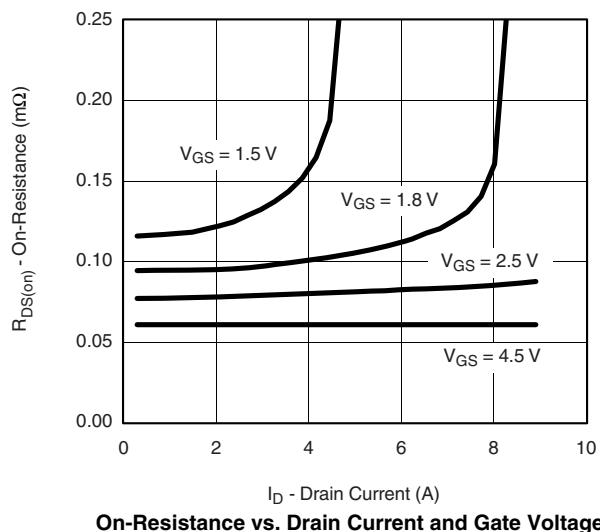
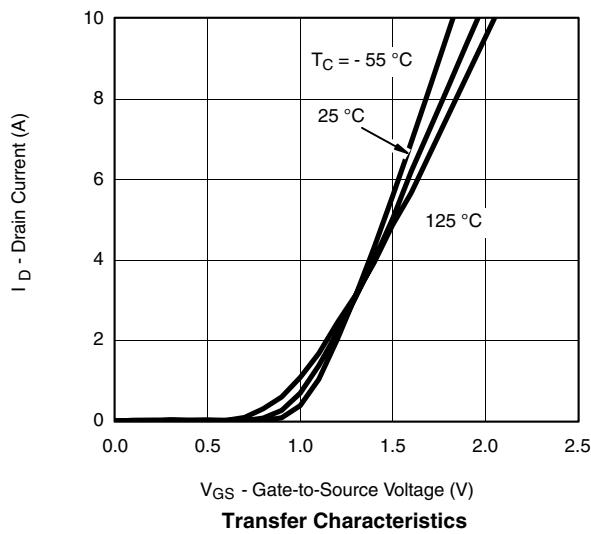
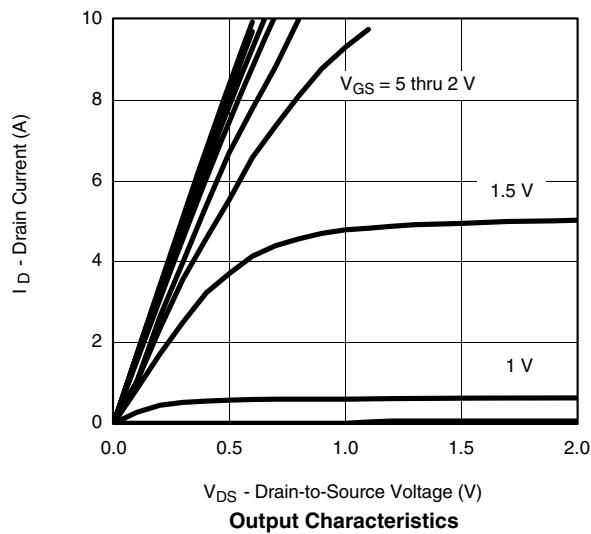
SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 8			V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = -250 \mu\text{A}$		- 9		mV/°C
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$			- 2.2		
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250 \mu\text{A}$	- 0.35		- 0.8	V
		$V_{DS} = V_{GS}, I_D = \pm 5 \text{ mA}$		- 0.55		
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 5 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -8 \text{ V}, V_{GS} = 0 \text{ V}$			- 1	μA
		$V_{DS} = -8 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$			- 10	
On-State Drain Current ^a	$I_{D(\text{on})}$	$V_{DS} \leq 5 \text{ V}, V_{GS} = -4.5 \text{ V}$	- 6.5			A
Drain-Source On-State Resistance ^a	$R_{DS(\text{on})}$	$V_{GS} = -4.5 \text{ V}, I_D = -2.0 \text{ A}$		0.0622	0.078	Ω
		$V_{GS} = -2.5 \text{ V}, I_D = -1.9 \text{ A}$		0.078	0.095	
		$V_{GS} = -1.8 \text{ V}, I_D = -0.8 \text{ A}$		0.094	0.115	
		$V_{GS} = -1.5 \text{ V}, I_D = -0.5 \text{ A}$		0.118	0.153	
		$V_{GS} = -1.2 \text{ V}, I_D = -0.100 \text{ A}$			0.424	
Forward Transconductance ^a	g_{fs}	$V_{DS} = -4 \text{ V}, I_D = -2.0 \text{ A}$		8		S
Dynamic^b						
Input Capacitance	C_{iss}	$V_{DS} = -4 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		650		pF
Output Capacitance	C_{oss}			220		
Reverse Transfer Capacitance	C_{rss}			122		
Total Gate Charge	Q_g	$V_{DS} = -4 \text{ V}, V_{GS} = -4.5 \text{ V}, I_D = -1.6 \text{ A}$		10.5	16	nC
Gate-Source Charge	Q_{gs}			1.3		
Gate-Drain Charge	Q_{gd}			1.9		
Gate Resistance	R_g	$f = 1 \text{ MHz}$		9.5		Ω
Turn-On Delay Time	$t_{d(\text{on})}$	$V_{DD} = -4 \text{ V}, R_L = 2 \Omega$ $I_D \approx -2 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$		9	14	ns
Rise Time	t_r			40	60	
Turn-Off Delay Time	$t_{d(\text{off})}$			50	75	
Fall Time	t_f			60	90	
Turn-On Delay Time	$t_{d(\text{on})}$	$V_{DD} = -4 \text{ V}, R_L = 2 \Omega$ $I_D \approx -2 \text{ A}, V_{GEN} = -8 \text{ V}, R_g = 1 \Omega$		8	15	ns
Rise Time	t_r			40	60	
Turn-Off Delay Time	$t_{d(\text{off})}$			46	70	
Fall Time	t_f			60	90	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	$T_C = 25^\circ\text{C}$			- 1.6	A
Pulse Diode Forward Current	I_{SM}				- 6.5	
Body Diode Voltage	V_{SD}	$I_S = -2.4 \text{ A}, V_{GS} = 0 \text{ V}$		- 0.7	- 1.2	V
Body Diode Reverse Recovery Time	t_{rr}	$I_F = -2.0 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$		25	38	ns
Body Diode Reverse Recovery Charge	Q_{rr}			7	11	nC
Reverse Recovery Fall Time	t_a			9		ns
Reverse Recovery Rise Time	t_b			16		

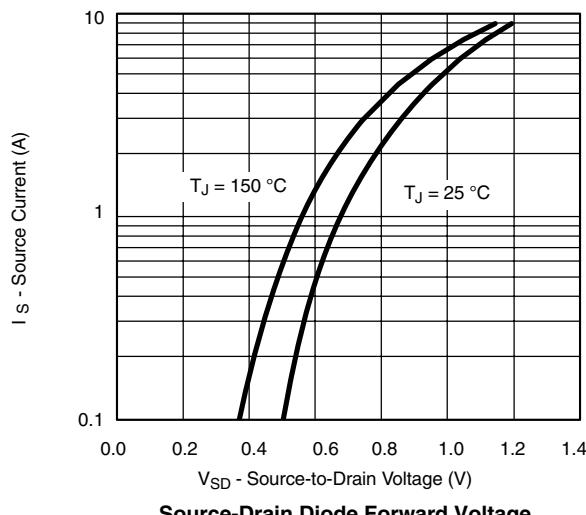
Notes:

- a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2 \%$.
 b. Guaranteed by design, not subject to production testing.

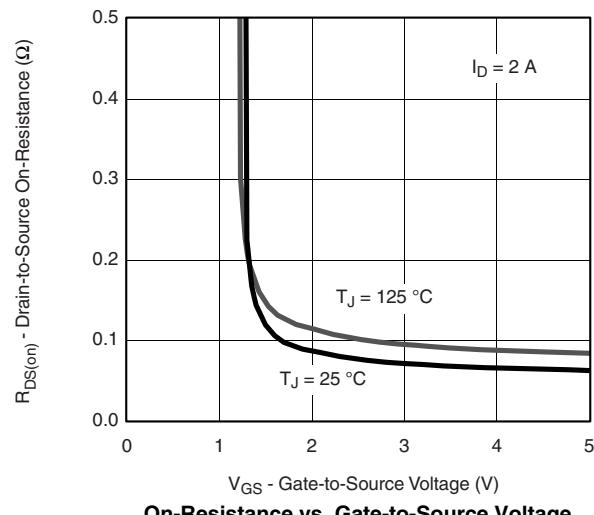
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


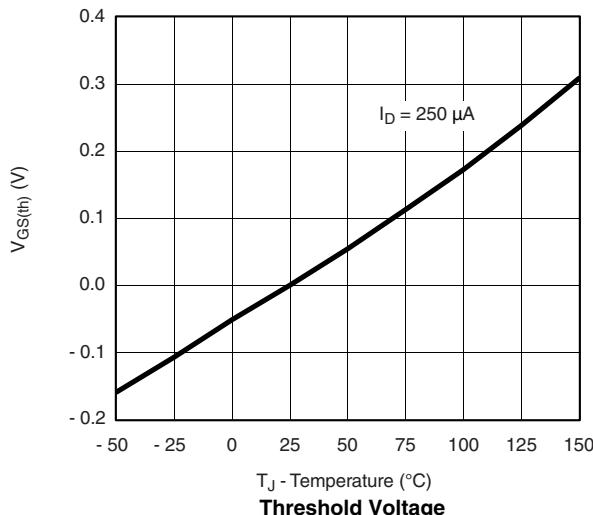
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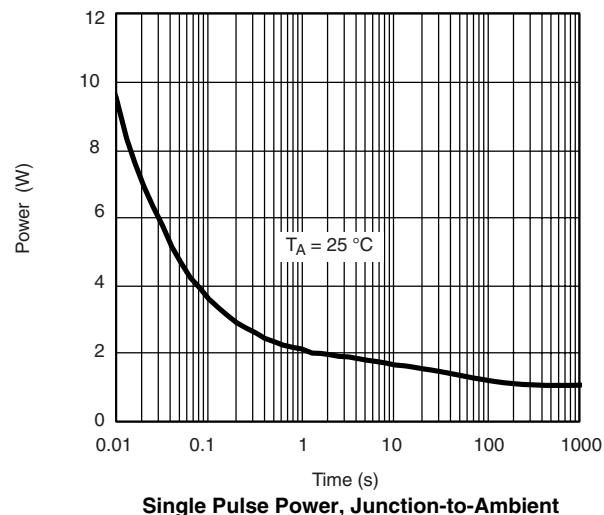
Source-Drain Diode Forward Voltage



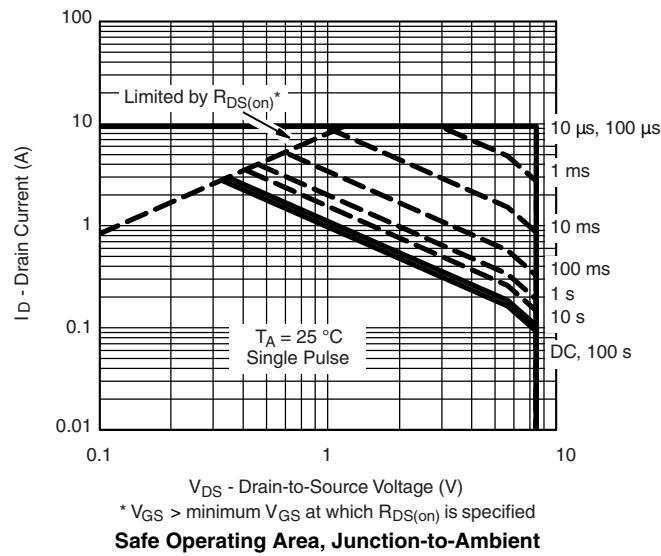
On-Resistance vs. Gate-to-Source Voltage



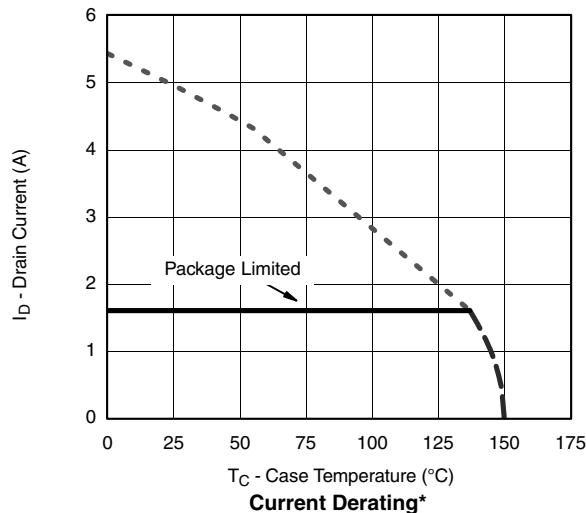
Threshold Voltage



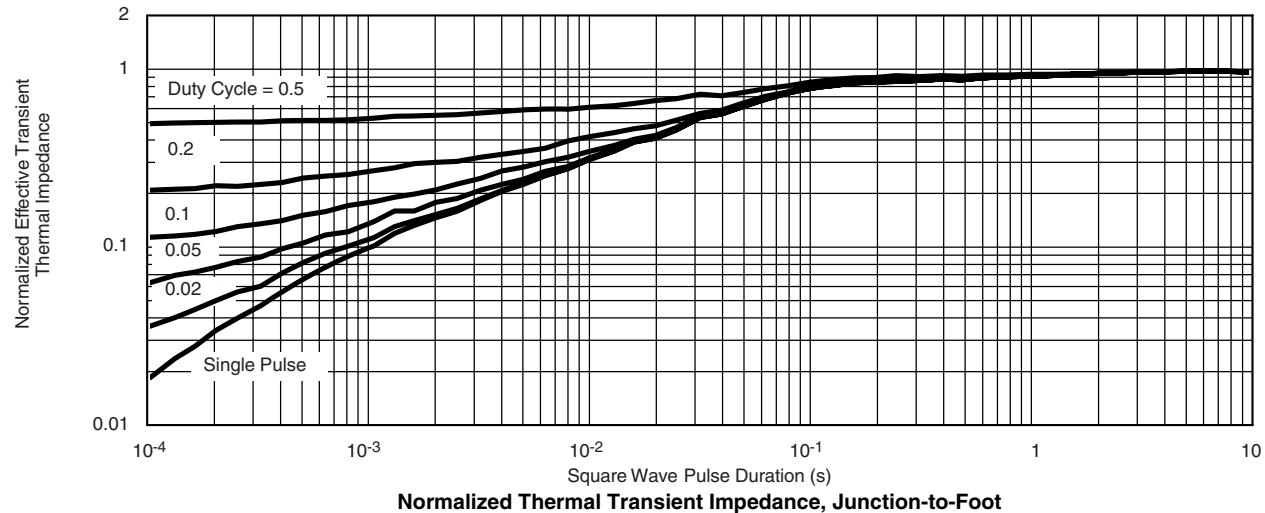
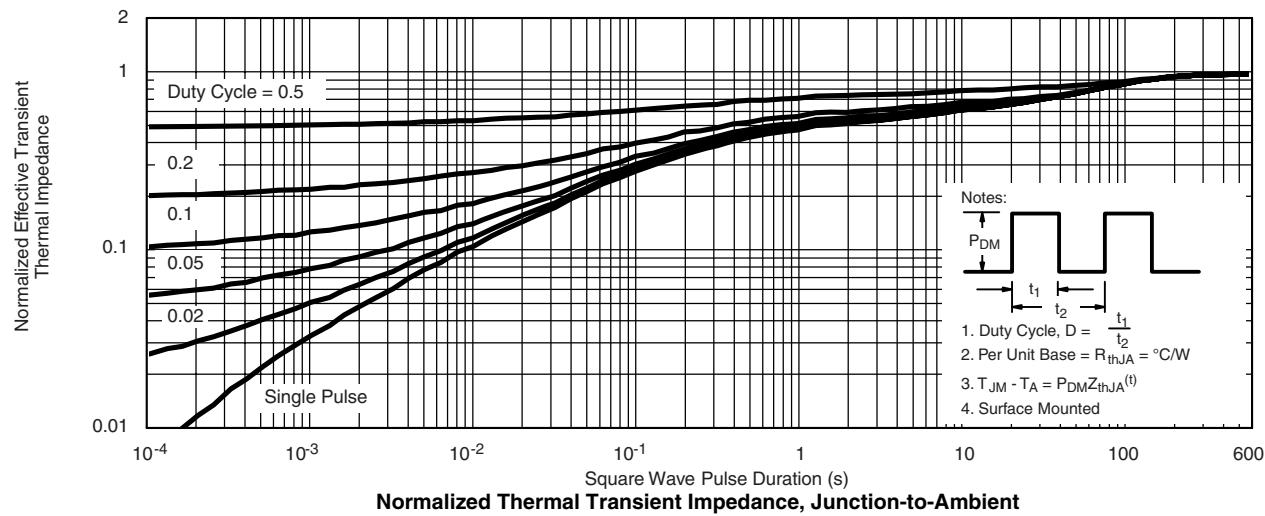
Single Pulse Power, Junction-to-Ambient



* $V_{GS} >$ minimum V_{GS} at which $R_{DS(on)}$ is specified
Safe Operating Area, Junction-to-Ambient

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


* The power dissipation P_D is based on T_{J(max)} = 175 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see <http://www.vishay.com/ppg?73338>.